Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/709,267	WU, KE	
Examiner	**Art Unit**	
Linh V. Nguyen	2819	

SEARCHED

Class	Subclass	Date	Examiner
330	251,152 257,259 260,261	3/28/2005	LN
327	52,87 206	3/28/2005	LN
326	65,71 81	3/28/2005	LN
326	83	3/28/2005	LN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
327	**206**	3/28/2005	**LN**
326	83	3/28/2005	LN

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
gate, self bias, current source, current sink, pull up, pull down, differential , bias	3/28/2005	LN